

Notes and News

Announcements and other items of crystallographic interest will be published under this heading at the discretion of the Editorial Board. The notes (in duplicate) should be sent to the Executive Secretary of the International Union of Crystallography (J. N. King, International Union of Crystallography, 13 White Friars, Chester CH1 1NZ, England). Publication of an item in a particular issue cannot be guaranteed unless the draft is received 8 weeks before the date of publication.

International Union of Crystallography Eighth International Congress: Abstracts

The communicated abstracts of the Congress, including Topical Meetings, have already been published in May 1969 as a 295-page supplement, part S3, of *Acta Crystallographica* Volume A25. This supplement is available at a price of D.kr. 75 (U.S. \$10.00, £4.4s.) from Munksgaard Limited, Prags Boulevard 47, DK-2300 Copenhagen S, Denmark.

Differing only in the outer covers and title pages, the abstracts are also available under the title *Collected Abstracts*, as provided to all Congress participants. This volume is available at a price of U.S. \$10.00 from the Polycrystal Book Service, P.O.Box 11567, Pittsburgh, Pa. 15238, U.S.A.

International Union of Crystallography *Early Papers on Diffraction of X-rays by Crystals*

The Executive Committee of the International Union of Crystallography has pleasure in announcing the publica-

tion in August 1969 of *Early Papers on Diffraction of X-rays by Crystals*, edited by J. M. Bijvoet, W. G. Burgers and G. Hägg. This book contains xvi + 372 pages, 93 figures and 8 plates. It has been published for the Union by A. Oosthoek's Uitg. Mij. N.V., Domstraat 9-13, Utrecht, Netherlands, from whom it can be obtained at a price of 48 Netherlands Guilders (U.S. \$13.50 or £5.14s. at the present rates of exchange). It is also obtainable from Polycrystal Book Service, P.O.Box 11567, Pittsburgh, Pa. 15238, U.S.A. or from any bookseller.

The volume contains extracts from more than 80 of the most important early papers on X-ray crystallography, arranged in such a way as both to form a history of the science and to serve as a teaching aid. The papers span the period 1912-1934. The five chapters are entitled: *The discovery of X-ray diffraction by crystals, interpretations and some of the first structure determinations; The reciprocal lattice; The intensity factors of the kinematical theory; The dynamical theory; The f-factor continued, extinction, anomalous scattering.* A second volume covering the development of X-ray crystallography in the 'trial-and-error' period and the (re)birth of the Fourier method is planned.

International Union of Crystallography

Commission on Crystallographic Apparatus Single-Crystal Radiation Damage Survey

Changes in the integrated intensities of some single-crystal reflexions have been observed as a function of increasing exposure to X-rays. With certain crystals, substantial variation has been noted in the first few hours while a more common pattern is of relatively small intensity changes over longer exposure periods. The integrated intensity of a given reflexion may either increase or decrease or be subjected to a combination of effects with different time dependences as the radiation damage continues. As a result, major systematic error may enter both the diffractometer measurement of intensity and the values of structure factors derived without adequate attention to the functional effects of radiation damage.

The Commission on Crystallographic Apparatus plans to conduct a preliminary survey of the extent to which systematic changes in integrated intensity are caused by radiation damage. All crystallographers making integrated intensity measurements with a diffractometer are cordially invited to take part in the survey. In order to encourage the widest possible participation, the experimental requirements of the survey are designed to be easily accommodated within normal crystal structure data collection procedures.

Participants will be invited to select a small group of reflexions, from a crystal of their choice (which may be one they are currently investigating), on the basis of relative magnitude and position in reciprocal space. The in-

tegrated intensities of this group are to be remeasured at periodic intervals throughout the duration of the experiment. It is expected that the participants' normal experimental time for crystal structure data collection will be increased only by a moderate amount on taking part in this survey. An indication of the sensitivity of various categories of chemical composition to radiation damage is likely to be among the results of this survey, which will be disseminated as soon as possible after its completion.

Details of the experimental information to be supplied by participants may be obtained from Commission member: Dr S. C. Abrahams, Bell Telephone Laboratories, Inc., Murray Hill, N.J. 07974, U.S.A.

Index of Crystallographic Supplies

The Commission on Crystallographic Apparatus plan to publish a new edition of the *Index of Crystallographic Supplies*. The readers of this Journal are urged to assist in the preparation of the *Index* by supplying us with the names and addresses of manufacturers and distributors of instruments and accessories used in X-ray diffraction studies. We are most interested in obtaining information regarding small, relatively unknown manufacturers of specialized accessories, in particular, those located outside the U.S.A. Please send all information to: Dr Reuben Rudman, Chemistry Department, Adelphi University, Garden City, New York 11530, U.S.A.